

To Advance Wafer Test Technology

o To Serve and Inform the Wafer Test Professional

o To Boldly Go Where No Workshop Has Gone Before

Long Beach, CA, June 1 to 4, 2003



WELCOME TO LONG BEACH



IEEE SWTW - 2003 June 1 to 4



COPYRIGHT NOTICE

- The presentations included in the SWTW proceedings reflect the authors opinions and are presented without change. Inclusion in the proceedings does not constitute an endorsement by the SouthWest Test Workshop Committee, IEEE Computer Society or the IEEE Test Technology Council.
- Papers previously copyrighted or with copyright restrictions cannot be presented. In keeping with a workshop environment and to avoid copyright issues, SWTW does not officially seek a copyright ownership / transfer from authors. Authors agree by submitting their work that their presentation is original work and substantially not published previously or copyrighted, may be referenced in the work of others, will be assembled / distributed in the SWTW Proceedings, and made available for download by anyone from the SWTW website.



WHAT IS SWTW - 2003?

- "THE" Conference for wafer test professionals
- Probe technology forum
- Not a theoretical or academic conference
- Provides practical solutions to real problems
- Mixture of vendor and user presentations
- Informal and relaxed atmosphere



INFORMAL CONFERENCE

- Long breaks
- Plenty of networking opportunities
- Informal discussions
- Numerous social activities
- Meet new people & have some fun!

(Don't tell the IEEE about the fun part)



SOCIAL ACTIVITIES

Monday after dinner *light exercise*

Probe Test Engineering Triathlon

- 1.5 Meter Cherry Seed Spitting
- 3 Meter Paper Airplane Toss for Accuracy
- 5 Meter Blindfolded Frisbee Throw

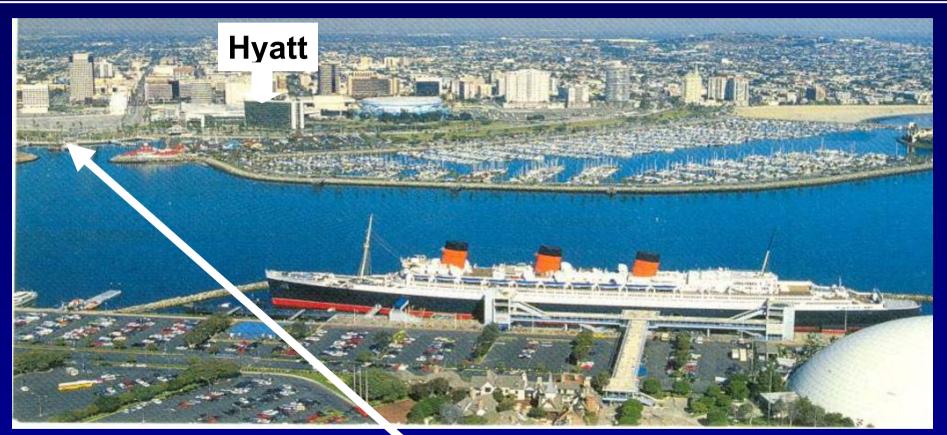
Team Event

- Three (3) individuals per team
- Must be from different companies
- All members participate in each event

IEEE SWTW - 2003 June 1 to 4



SOCIAL ACTIVITIES

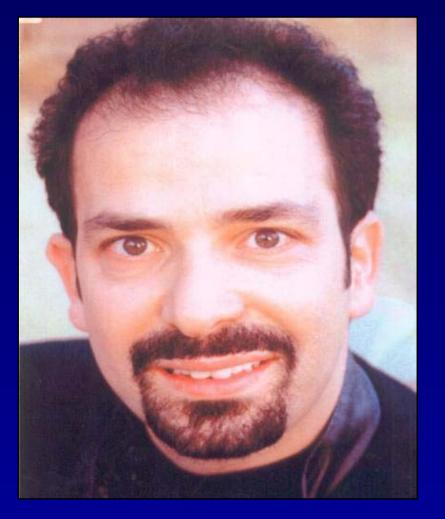


Tuesday Afternoon Harbor Sightseeing Cruise

IEEE SWTW - 2003 June 1 to 4



SOCIAL ACTIVITIES



Tuesday Evening

 Triathlon Awards Banquet

Comedian...
Nazareth
"American By Choice"

IEEE SWTW - 2003 June 1 to 4



SWTW – 2003 COMMITTEE

Organization and Technical Program

- William Mann, SWTW General Chair
- Jerry Broz, Ph.D., Point Technologies, Technical Program Chair
- Maddie Harwood, CEM Inc, Registration and Finance Chair

• Technical Committee and Session Chairs

- Michael Egloff, AMD
- Tom Foerster, Jazz Semiconductor
- Gavin Gibson, Infineon Technologies
- Michael Harris, Texas Instruments
- Ken Karklin, Agilent Technologies
- Ger Koch, Philips Semiconductor

- Rey Rincon, Kulicke and Soffa
- Phil Seitzer, Agere Systems
- Roger Sinsheimer, Xandex
- Tim Swettlen, Intel
- Fred Taber, IBM Microelectronics
- Bill Williams, Motorola



TECHNICAL PROGRAM

• Sunday, June 1, 2003

- Tutorial: The Impact of Design For Test on the Cost of Test
- Keynote Speaker Brian Matas (VP of IC Insights)

"The IC Market Recovery Outlook"

• Monday, June 2, 2003

- New Probe Technologies Potpourri
- Advances in Memory Probing
- Vertical Probe Technologies
- Metal Stack and Dielectric Characterization
- Cocktail Reception & Dinner
- Probe Test Engineering Triathlon

IEEE SWTW - 2003 June 1 to 4



TECHNICAL PROGRAM

• Tuesday, June 3, 2003

- MEMs Technologies
- Controlling Contact Resistance
- Afternoon Social Activities
 - Long Beach Harbor Sight Seeing Cruise
- Cocktail Reception
- Dinner and Comedy Entertainment

• Wednesday June 4, 2003

- Probe Process Characterization and Improvement
- Advances in Probe Card Analyzers
- Best Presentation Awards

IEEE SWTW - 2003 June 1 to 4



RECOGNITION & AWARDS

- Best Overall Presentation
- Best Data Presented
- Best Presentation, Tutorial in Nature
- Most "Inspirational" Presentation
- Engineering Triathlon Winners
- Other "Special Awards"



Brett Grossman and Tim Swettlen, Intel

"Modeling Distributed Power Delivery Effects in High Performance Sort Interface Units"

Sam McKnight, <u>IBM Microelectronics</u>

"Probing Lead Free Solder Bumps in Final Wafer Test"

• William Knauer, <u>Keithley Instruments, Inc.</u>

"RF S-Parameter Measurements - A Production Solution"

• Rainer Gaggl, Ph.D., <u>T.I.P.S. Messtechnik GmbH</u>

"Probing 10 kV and 100 Amps: Challenges and Solutions for High Voltage / High Current Wafer Probing"

IEEE SWTW - 2003 June 1 to 4



http://www.swtest.org

Central Online Repository

- Past presentations
- Online registration
- With more features to come......

• Tremendous continued success!!

- Over eight thousand visits to the site last year
- Thanks to "web-efforts" of Jerry Broz



We think of everything, almost...

Souvenirs and a "Post Card Home"

"You get to go to Long Beach and have a lot of fun.....

..... and all I get is this crummy toy!"

Long Beach, CA Page 16

IEEE SWTW - 2003 June 1 to 4